Application/Control No. 09/735,860 Reexamination CHANG ET AL. Examiner Meless N Zewdu Applicant(s)/Patent Under Reexamination CHANG ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,740,164	04-1998	Liron	370/316
	В	US-5,589,834	12-1996	Weinberg	342/354
	С	US-5,852,721	12-1998	Dillon et al.	395/200.47
	D	US-6,339,707 B1	01-2002	Wainfan et al.	455/427
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					,
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.